

Notice of References Cited	Application/Control No. 10/613,922	Applicant(s)/Patent Under Reexamination UTTERBERG, DAVID S.	
	Examiner Mark K Han	Art Unit 3763	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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B		US-			
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Mark K Han
3/1/05

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